



XRF-Spectrometer LXRF-A10

XRF-SPECTROMETER LXRF-A10

XRF-Spectrometer LXRF-A1O is a microprocessor controlled high-count throughput unit with low detection limits for wide range of elements. Provision of multi-elemental analysis with detection limits upto 1 ppm. Built-in movable platform for easy location of testing point. High resolution detector improves analysis accuracy. Equipped with safety features of optical tube shielding with no X-ray radiation and high voltage emergency locking.

Features _

- Detection limit 1 ppm
- Measureable elements S to U
- Elemental content 1 ppm to 99 %
- Movable sample platform for easy detection of testing point
- Built-in electric cooling Si-PIN detector
- Safety features optical tube shielding with no X-ray radiation and high voltage emergency locking

Applications

Used in detection of plating thickness of metals, concentration of plating solution , RoHS detection and analysis, full-element analysis and electro plating industries

Specifications

| Model No. | LRXF-A10 |
|----------------------|--------------------|
| Measureable elements | S to U |
| Detection limit | 1 ppm |
| Temperature | 15 ~ 30 °C |
| Elemental content | 1 ppm to 99 % |
| Repeatability | 0.1 % |
| Stability | 0.1 % |
| Power supply | AC 220 V ± 5 V |
| Dimensions | 550 x 410 x 320 mm |
| Weight | 45 kg |